Microsemi
POWER PRODUCTS GROUP

Power MOS 8 Cooler!™

APT25M100J

1000V, 25A, 0.33Ω Max

N-Channel MOSFET

Power MOS 8™ is a high speed, high voltage N-channel switch-mode power MOSFET. A proprietary planar stripe design yields excellent reliability and manufacturability. Low switching loss is achieved with low input capacitance and ultra low C_{rss} "Miller" capacitance. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control slew rates during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency. Reliability in flyback, boost, forward, and other circuits is enhanced by the high avalanche energy capability.

ISOTOP®

APT25M100J

Single die MOSFET

FEATURES

- **Fast switching with low EMI/RFI**
- **Low $R_{DS(on)}$**
- **Ultra low C_{rss} for improved noise immunity**
- **Low gate charge**
- **Avalanche energy rated**
- **RoHS compliant**

TYPICAL APPLICATIONS

- **PFC and other boost converter**
- **Buck converter**
- **Two switch forward (asymmetrical bridge)**
- **Single switch forward**
- **Flyback**
- **Inverters**

Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
I_D	Continuous Drain Current @ T_C = 25°C	25	A
	Continuous Drain Current @ T_C = 100°C	16	
I_{DM}	Pulsed Drain Current ①	140	
V_{GS}	Gate-Source Voltage	±30	V
E_{AS}	Single Pulse Avalanche Energy ②	2165	mJ
I_{AR}	Avalanche Current, Repetitive or Non-Repetitive	18	A

Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Typ	Max	Unit
P_D	Total Power Dissipation @ T_C = 25°C			545	W
$R_{\theta JC}$	Junction to Case Thermal Resistance			0.23	°C/W
$R_{\theta CS}$	Case to Sink Thermal Resistance, Flat, Greased Surface		0.15		
T_J,T_{STG}	Operating and Storage Junction Temperature Range	-55		150	°C
$V_{Isolation}$	RMS Voltage (50-60hHz Sinusoidal Waveform from Terminals to Mounting Base for 1 Min.)	2500			V
W_T	Package Weight		1.03		oz
			29.2		g
Torque	Terminals and Mounting Screws.			10	in·lbf
				1.1	N·m

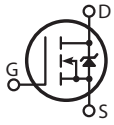
Static Characteristics T_J = 25°C unless otherwise specified APT25M100J

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
$V_{BR(DSS)}$	Drain-Source Breakdown Voltage	V_{GS} = 0V, I_D = 250µA	1000			V
$\Delta V_{BR(DSS)}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I_D = 250µA		1.15		V/°C
$R_{DS(on)}$	Drain-Source On Resistance③	V_{GS} = 10V, I_D = 18A		0.29	0.33	Ω
$V_{GS(th)}$	Gate-Source Threshold Voltage	V_{GS} = V_{DS}, I_D = 2.5mA	3	4	5	V
$\Delta V_{GS(th)}/\Delta T_J$	Threshold Voltage Temperature Coefficient			-10		mV/°C
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS} = 1000V, T_J = 25°C			100	µA
		V_{GS} = 0V, T_J = 125°C			500	
I_{GSS}	Gate-Source Leakage Current	V_{GS} = ±30V			±100	nA

Dynamic Characteristics T_J = 25°C unless otherwise specified

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
g_{fs}	Forward Transconductance	V_{DS} = 50V, I_D = 18A		39		S
C_{iss}	Input Capacitance	V_{GS} = 0V, V_{DS} = 25V f = 1MHz		9835		pF
C_{rss}	Reverse Transfer Capacitance			130		
C_{oss}	Output Capacitance			825		
$C_{o(cr)}$ ④	Effective Output Capacitance, Charge Related	V_{GS} = 0V, V_{DS} = 0V to 667V		335		
$C_{o(er)}$ ⑤	Effective Output Capacitance, Energy Related			170		
Q_g	Total Gate Charge	V_{GS} = 0 to 10V, I_D = 18A, V_{DS} = 500V		305		nC
Q_{gs}	Gate-Source Charge			55		
Q_{gd}	Gate-Drain Charge			145		
$t_{d(on)}$	Turn-On Delay Time	**Resistive Switching** V_{DD} = 667V, I_D = 18A R_G = 2.2Ω⑥, V_{GG} = 15V		44		ns
t_r	Current Rise Time			40		
$t_{d(off)}$	Turn-Off Delay Time			150		
t_f	Current Fall Time			38		

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
I_S	Continuous Source Current (Body Diode)	MOSFET symbol showing the integral reverse p-n junction diode (body diode) 			25	A
I_{SM}	Pulsed Source Current (Body Diode)①				140	
V_{SD}	Diode Forward Voltage	I_{SD} = 18A, T_J = 25°C, V_{GS} = 0V			1	V
t_{rr}	Reverse Recovery Time	I_{SD} = 18A③ di_{SD}/dt = 100A/µs, T_J = 25°C		1165		ns
Q_{rr}	Reverse Recovery Charge			33		µC
dv/dt	Peak Recovery dv/dt	I_{SD} ≤ 18A, di/dt ≤1000A/µs, V_{DD} = 100V, T_J = 125°C			10	V/ns

① Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.

② Starting at T_J = 25°C, L = 13.36mH, R_G = 2.2Ω, I_{AS} = 18A.

③ Pulse test: Pulse Width < 380µs, duty cycle < 2%.

④ $C_{o(cr)}$ is defined as a fixed capacitance with the same stored charge as C_{OSS} with V_{DS} = 67% of $V_{(BR)DSS}$.

⑤ $C_{o(er)}$ is defined as a fixed capacitance with the same stored energy as C_{OSS} with V_{DS} = 67% of $V_{(BR)DSS}$. To calculate $C_{o(er)}$ for any value of V_{DS} less than $V_{(BR)DSS,}$ use this equation: $C_{o(er)}$ = -2.85E-7/V_{DS}^2 + 5.04E-8/V_{DS} + 9.75E-11.

⑥ R_G is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

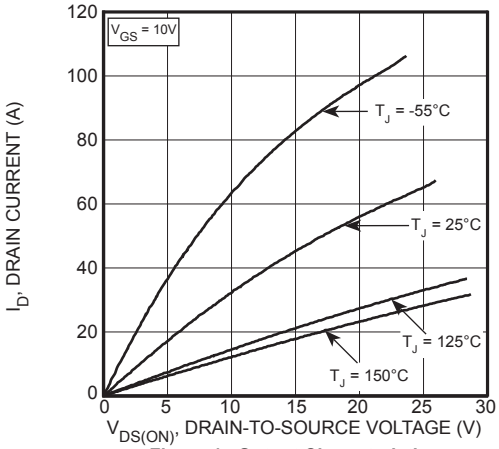


Figure 1, Output Characteristics

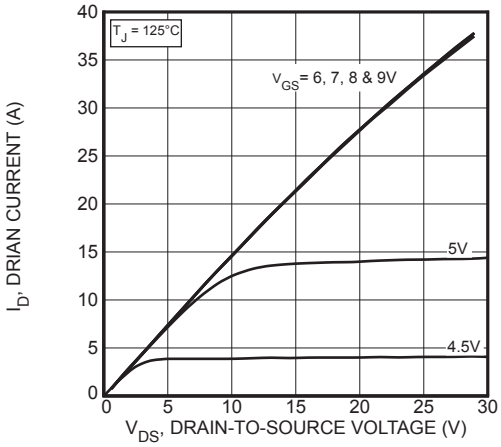


Figure 2, Output Characteristics

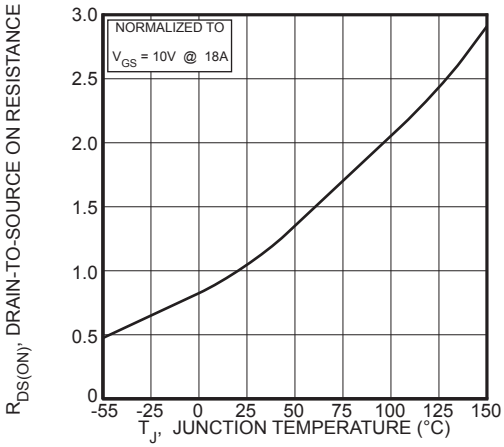


Figure 3, $R_{DS(ON)}$ vs Junction Temperature

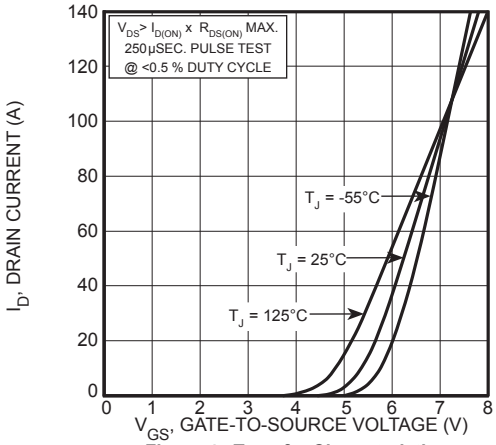


Figure 4, Transfer Characteristics

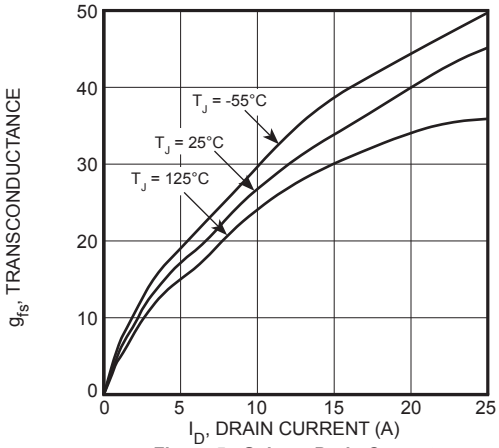


Figure 5, Gain vs Drain Current

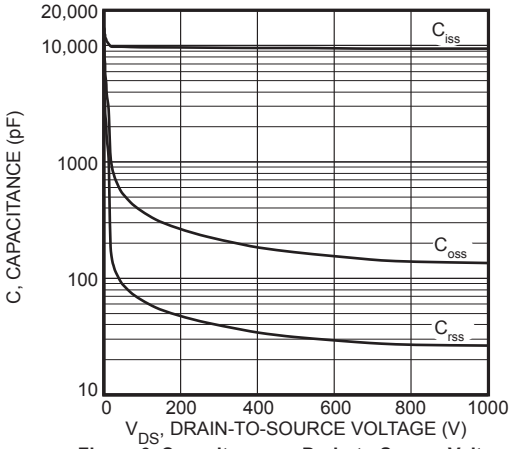


Figure 6, Capacitance vs Drain-to-Source Voltage

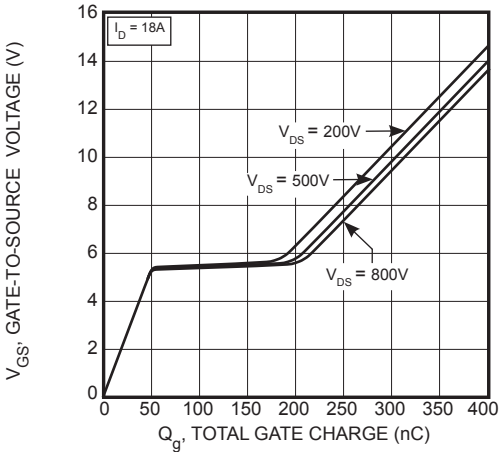


Figure 7, Gate Charge vs Gate-to-Source Voltage

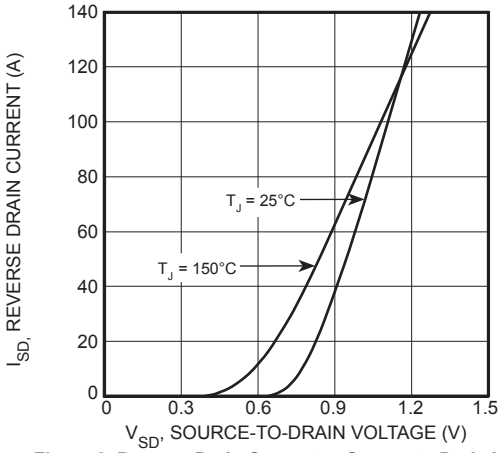


Figure 8, Reverse Drain Current vs Source-to-Drain Voltage